EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	2	"20030071331"	US-PGPUB; USPAT; USOCR; FPRS	ADJ	ON	2007/11/23 11:11
S1	36134	wire bonding	US-PGPUB; USPAT; USOCR; FPRS	ADJ	ON	2007/11/19 19:07
S2	24147	wire bonding and @ad<"20030922"	US-PGPUB; USPAT; USOCR; FPRS	ADJ	ON	2007/11/19 19:07
S3	31	wire bonding probe bump and @ad<"20030922"	US-PGPUB; USPAT; USOCR; FPRS	WITH	ON	2007/11/19 19:10
S4	9	("4894605" | "5166602" | "5397996" | "5506510").PN. OR ("6249114").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/11/19 19:09
S5	75	wire (bonding or contact$3 or connect$3) probe bump and @ad<"20030922"	US-PGPUB; USPAT; USOCR; FPRS	WITH	ON	2007/11/19 19:10
S6	7	wire (bonding or contact$3 or connect$3) probe adj bump and @ad<"20030922"	US-PGPUB; USPAT; USOCR; FPRS	WITH	ON	2007/11/19 19:12
S7	0	wire adj terminals(bonding or contact$3 or connect$3) probe adj bump and @ad<"20030922"	US-PGPUB; USPAT; USOCR; FPRS	WITH	ON	2007/11/19 19:12
S8	0	wire adj terminals test$3 probe adj bump and @ad<"20030922"	US-PGPUB; USPAT; USOCR; FPRS	WITH	ON	2007/11/19 19:12
S9	0	wire adj terminals test$3 probe adj bump and @ad<"20030922"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	WITH	ON	2007/11/19 19:12
S10	0	terminals test$3 probe adj bump and @ad<"20030922"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	WITH	ON	2007/11/19 19:12
S11	0	wir$3 terminals test$3 probe adj bump and @ad<"20030922"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2007/11/19 19:13

EAST Search History

S12	0	wir$3 terminals test$3 adj bump and @ad<"20030922"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2007/11/19 19:13
S13	19	wir$3 test$3 adj bump and @ad<"20030922"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2007/11/19 19:16
S14	495	bump adj electrode contact$3 wir$3 and @ad<"20030922"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2007/11/19 19:18
S15	24	probe bump adj electrode contact$3 wir$3 and @ad<"20030922"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2007/11/19 19:23
S16	19	probe bump adj electrode contact$3 test wafer and @ad<"20030922"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2007/11/19 19:24
S17	194	probe near6 bump contact$3 test wafer and @ad<"20030922"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2007/11/19 19:25
S18	74	probe near6 bump contact$3 test wir$3 and @ad<"20030922"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2007/11/19 19:28
S19	30	probe near2 bump contact$3 test wir$3 and @ad<"20030922"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2007/11/19 19:29
S20	161	probe near2 bump and test wir$3 and @ad<"20030922"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2007/11/19 19:30

S21	55	probe near2 bump and test near4 wir$3 and @ad<"20030922"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2007/11/19 19:35
S22	40	(probe or test)near2 electrode near2 bump (wir$3 or pads) and @ad<"20030922"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2007/11/19 19:40
S23	0	probe card for ic testers.ti.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	WITH	ON	2007/11/19 19:40
S24	22	probe card ic testers.ti.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	WITH	ON	2007/11/19 19:41
S25	309	probe card ic .ti.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	WITH	ON	2007/11/19 19:43
S26	16	probe card ic wir$3.ti.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	WITH	ON	2007/11/19 19:44
S27	0	probe card physically contact$3 ic wir$3	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	WITH	ON	2007/11/19 19:45
S28	2	probe card physically contact$3 wir$3	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	WITH	ON	2007/11/19 19:46
S29	1	probe bump physically contact$3 wir$3	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	WITH	ON	2007/11/19 19:46

S30	8	bump physically contact$3 wir$3	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	WITH	ON	2007/11/19 19:48
S31	2956	bump contact$3 wir$3	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	WITH	ON	2007/11/19 19:48
S32	48	probe card bump contact$3 wir$3	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	WITH	ON	2007/11/19 19:54
S33	158	probe bump contact$3 wir$3	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	WITH	ON	2007/11/19 20:03
S34	0	"2003124274"	US-PGPUB; USPAT; USOCR; FPRS	OR	ON	2007/11/19 20:03
S35	2	"2003124274"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/19 20:04
S36	19	"737943"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/19 20:05
S37	2	"200222809"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/19 20:05
S38	16891	438/612,106-126.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/11/19 20:06

S39	28	pads wir$3 probe card and 438/612,106-126.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2007/11/19 20:15
S40	19	"6705876"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2007/11/19 20:12
S41	26	contact near4 (wir$3 or elements) probe card and 438/612, 106-126.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2007/11/19 20:15
S42	103	contact near4 (wir$3 or elements) probe card and "438".clas.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2007/11/19 20:16
S43	103	contact near4 (wir$3 or elements) probe adj card and "438". clas.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2007/11/19 20:16
S44	8	contact near4 (wir$3 or elements) probe adj card and 438/612. ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2007/11/19 20:20
S45	22	contact near4 (wir$3 or elements or trace) and probe adj card and 438/612.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2007/11/19 20:33
S46	3758	probe near (bump or ball or contact) same (wir$3 or trace or line)	US-PGPUB; USPAT; USOCR; FPRS	OR	ON	2007/11/19 20:46
S47	2976	probe near (bump or ball or contact) same (wir$3 or trace or leads)	US-PGPUB; USPAT; USOCR; FPRS	OR	ON	2007/11/19 20:46
S48	6657819	probe near (bump or ball or contact) (contact$3 or connect$3 or touching) (wir$3 or trace or leads)	US-PGPUB; USPAT; USOCR; FPRS	OR	ON	2007/11/19 20:47

EAST Search History

S49	2958	probe near (bump or ball or contact) (contact$3 or connect$3 or touching) (wir$3 or trace or leads)	US-PGPUB; USPAT; USOCR; FPRS	SAME	ON	2007/11/19 20:47
S50	1452	probe near (bump or ball or contact) (contact$3 or connect$3 or touching) (wir$3 or trace or leads)	US-PGPUB; USPAT; USOCR; FPRS	WITH	ON	2007/11/19 20:48
S51	1097	probe near (bump or ball or contact) (contact$3 or connect$3 or touching) (wir$3 or trace or leads) and @ad<"20040809"	US-PGPUB; USPAT; USOCR; FPRS	WITH	ON	2007/11/19 20:49
S52	43	probe near (bump or ball) (contact$3 or connect$3 or touching) (wir$3 or trace or leads) and @ad<"20040809"	US-PGPUB; USPAT; USOCR; FPRS	WITH	ON	2007/11/19 20:49
S53	12	probe adj (bump or ball) (contact$3 or connect$3 or touching) (wir$3 or trace or leads) and @ad<"20040809"	US-PGPUB; USPAT; USOCR; FPRS	WITH	ON	2007/11/19 20:52
S54	201	probe adj (bump or ball or head) (contact$3 or connect$3 or touching) (wir$3 or trace or leads) and @ad<"20040809"	US-PGPUB; USPAT; USOCR; FPRS	WITH	ON	2007/11/19 21:00
S55	115	probe adj card same wir$3 pattern	US-PGPUB; USPAT; USOCR; FPRS	ADJ	ON	2007/11/19 21:00
S56	80	probe adj card same wir$3 pattern and @ad<"20040809"	US-PGPUB; USPAT; USOCR; FPRS	ADJ	ON	2007/11/19 21:04
S57	0	probe adj card same wir$3 pattern near circuit adj baord and @ad<"20040809"	US-PGPUB; USPAT; USOCR; FPRS	ADJ	ON	2007/11/19 21:04
S58	0	probe adj card same wir$3 pattern near circuit adj boa'rd and @ad<"20040809"	US-PGPUB; USPAT; USOCR; FPRS	ADJ	ON	2007/11/19 21:04
S59	0	probe adj card same wir$3 pattern near circuit adj board and @ad<"20040809"	US-PGPUB; USPAT; USOCR; FPRS	ADJ	ON	2007/11/19 21:04
S60	4	probe adj card and wir$3 pattern near circuit adj board and @ad<"20040809"	US-PGPUB; USPAT; USOCR; FPRS	ADJ	ON	2007/11/19 21:05
S61	4	probe adj card and (wir$3 or trace or lead)pattern near circuit adj board and @ad<"20040809"	US-PGPUB; USPAT; USOCR; FPRS	ADJ	ON	2007/11/19 21:05
S62	4	probe adj card and (wir$3 or trace or lead)pattern near circuit adj board and @ad<"20040809"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/11/19 21:05

EAST Search History

S63	401	probe adj card and (wir$3 or trace or lead)pattern and @ad<"20040809"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/11/19 21:06
S64	206	probe adj card same(wir$3 or trace or lead)pattern and @ad<"20040809"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/11/19 21:08
S65	388	(probe adj card or prober or tester)same(wir$3 or trace or lead)pattern and @ad<"20040809"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/11/19 21:08
S66	1133	test$3 with (wir$3 or trace or lead)pattern and @ad<"20040809"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/11/19 21:12
S67	113	test$3 with (wir$3 or trace or lead)pattern and probe adj card and @ad<"20040809"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/11/19 21:16
S68	1731	circuit adj board and probe adj card and @ad<"20040809"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/11/19 21:17
S69	1008	circuit adj board same probe adj card and @ad<"20040809"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/11/19 21:17
S70	779	circuit adj board with probe adj card and @ad<"20040809"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/11/19 21:17
S71	0	circuit adj board testing probe adj card and @ad<"20040809"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/11/19 21:17

EAST Search History

S72	162	circuit adj board testing probe adj card and @ad<"20040809"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	WITH	ON	2007/11/19 21:17
S73	59	(wirings or traces)(circuit adj board or wafer) testing probe adj card and @ad<"20040809"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	WITH	ON	2007/11/19 21:19
S74	13	(wirings or traces)(circuit adj board) testing probe adj card and @ad<"20040809"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	WITH	ON	2007/11/19 21:20
S75	13	probe adj card testing (wirings or traces)(circuit adj board) and @ad<"20040809"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	WITH	ON	2007/11/19 21:20
S76	169	probe adj card testing (wirings or traces) and @ad<"20040809"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	WITH	ON	2007/11/19 21:27
S77	0	saki-hiroshi.in.	US-PGPUB; USPAT; USOCR; FPRS	OR	ON	2007/11/19 21:27
S78	255	sakai-hiroshi.in.	US-PGPUB; USPAT; USOCR; FPRS	OR	ON	2007/11/19 21:27
S79	9	("4894605" | "5166602" | "5397996" | "5506510").PN. OR ("6249114").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/11/19 21:31
S80	13	("5089772" | "5399904" | "5455460" | "5506499" | "5585676" | "5814891" | "5886409" | "5895978" | "5909034" | "5955789" | "5956567" | "5965903" | "6249114").PN. OR ("6448783").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/11/19 21:32
S81	47	("5216278" | "5382827" | "5433822" | "5523622" | "5581122" | "5583377" | "5598036" | "5640048").PN. OR ("5886409"). URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/11/19 21:37
S82	2	matsushita electtric industrial co.as.	US-PGPUB; USPAT; USOCR; FPRS	NEAR	ON	2007/11/19 21:39
S83	33210	matsushita electric industrial co.as.	US-PGPUB; USPAT; USOCR; FPRS	NEAR	ON	2007/11/19 21:39

S84	33206	matsushita electric industrial co.as.	US-PGPUB; USPAT; USOCR; FPRS	ADJ	ON	2007/11/19 21:39
S85	40	probe adj card and matsushita electric industrial co.as.	US-PGPUB; USPAT; USOCR; FPRS	ADJ	ON	2007/11/19 21:42
S86	777	probe and matsushita electric industrial co.as.	US-PGPUB; USPAT; USOCR; FPRS	ADJ	ON	2007/11/19 21:42
S87	84	(first or second or plural$3 or multiple)(wir$3 leads or trace) contact$3 one bump	US-PGPUB; USPAT; USOCR; FPRS	WITH	ON	2007/11/19 21:48
S88	21	(first or second or plural$3 or multiple)near (wir$3 leads or trace) contact$3 one bump	US-PGPUB; USPAT; USOCR; FPRS	WITH	ON	2007/11/19 21:49
S89	7	(wir$3 leads or trace) contact$3 one adj bump	US-PGPUB; USPAT; USOCR; FPRS	WITH	ON	2007/11/19 21:49
S90	17	(wir$3 leads or trace) contact$3 one adj (bump or ball)	US-PGPUB; USPAT; USOCR; FPRS	WITH	ON	2007/11/19 21:50
S91	143	wir$3 (contact$3 or connect$3) one adj (bump or ball)	US-PGPUB; USPAT; USOCR; FPRS	WITH	ON	2007/11/19 21:55
S92	1	wir$3 (contact$3 or connect$3) one adj (bump or ball)probe	US-PGPUB; USPAT; USOCR; FPRS	WITH	ON	2007/11/19 21:56
S93	138	wir$3 (contact$3 or connect$3) one adj probe	US-PGPUB; USPAT; USOCR; FPRS	WITH	ON	2007/11/19 21:58
S94	179	probe card wiring board	US-PGPUB; USPAT; USOCR; FPRS	WITH	ON	2007/11/19 21:59
S95	25	probe card with bumps wiring board	US-PGPUB; USPAT; USOCR; FPRS	WITH	ON	2007/11/19 22:02
S96	1446	probing (wir$3 or leads)	US-PGPUB; USPAT; USOCR; FPRS	WITH	ON	2007/11/19 22:03
S97	1065	probing (wir$3 or leads)and @ad<"20040809"	US-PGPUB; USPAT; USOCR; FPRS	WITH	ON	2007/11/19 22:04
S98	131	probing (wir$3 or leads)and @ad<"20040809"	US-PGPUB; USPAT; USOCR; FPRS	NEAR	ON	2007/11/19 22:04

EAST Search History

S99	4	probe card test$3 wire adj bond	US-PGPUB; USPAT; USOCR; FPRS	WITH	ON	2007/11/20 09:26
S100	50	probe card test$3 wire adj bond	US-PGPUB; USPAT; USOCR; FPRS	SAME	ON	2007/11/20 09:26
S101	234	("3766439" | "4169642" | "4341842" | "4597617" | "4679118" | "4859189" | "4922376").PN. OR ("5123850").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/11/20 09:43
S102	27	probe near(contacts or terminals) with (wir$3 or traces or leads)near device	US-PGPUB; USPAT; USOCR; FPRS	OR	ON	2007/11/20 09:46
S103	627894	testing(contacts or terminals) with (wir$3 or traces or leads)near device	US-PGPUB; USPAT; USOCR; FPRS	OR	ON	2007/11/20 09:47
S104	104	testing(contacts or terminals) with (wir$3 or traces or leads)near device	US-PGPUB; USPAT; USOCR; FPRS	WITH	ON	2007/11/20 10:01
S105	22	probe adj card near4 bump with wir$3 and 324/754-757,756. ccls.	US-PGPUB; USPAT; USOCR; FPRS	OR	ON	2007/11/20 10:04
S106	129	probe adj card near4 bump and 324/754-757,756.ccls.	US-PGPUB; USPAT; USOCR; FPRS	OR	ON	2007/11/20 10:05
S107	1837	pads (connect$3 or contact$3 or bond$2)(wir$3) and probe adj card	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2007/11/20 10:07
S108	1300	pads (connect$3 or contact$3 or bond$2)(wir$3) and probe adj card	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	WITH	ON	2007/11/20 10:07
S109	869	pads near4(connect$3 or contact$3 or bond$2)near4 (wir$3) and probe adj card	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	WITH	ON	2007/11/20 10:08
S110	194	"30922"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	WITH	ON	2007/11/20 10:08

S11 1	584	pads near4(connect$3 or contact$3 or bond$2)near4 (wir$3) and probe adj card and @ad<"20030922"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	WITH	ON	2007/11/20 10:20
S11 2	14	pads near4(connect$3 or contact$3 or bond$2)near4 (wir$3) (connect$3 or contact$3 or bond$2)near4 probe adj card and @ad<"20030922"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	WITH	ON	2007/11/20 10:23
S11 3	169	(wir$3) (connect$3 or contact$3 or bond$2)near4 probe adj card and @ad<"20030922"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	WITH	ON	2007/11/20 10:27
S11 4	1887	test$3 wir$3 (contact$3 or bond$2 or connect$3) pad	US-PGPUB; USPAT; USOCR; FPRS	WITH	ON	2007/11/20 10:28
S11 5	1326	test$3 wir$3 (contact$3 or bond$2 or connect$3) pad and @ad<"20030922"	US-PGPUB; USPAT; USOCR; FPRS	WITH	ON	2007/11/20 10:29
S11 6	52	test$3 wir$3 (contact$3 or bond$2 or connect$3) pad and probe adj card with bump and @ad<"20030922"	US-PGPUB; USPAT; USOCR; FPRS	WITH	ON	2007/11/20 10:29
S11 7	62	("3795973" | "5008727" | "5089772" | "5187020" | "5241266" | "5307010").PN. OR ("5554940").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/11/20 10:34
S11 8	0	semicondcutor adj wafer wir$3 and probe adj card near6 bumps	US-PGPUB; USPAT; USOCR; FPRS	WITH	ON	2007/11/20 10:34
S11 9	0	semicondcutor adj wafer wir$3 and probe adj card near6 bumps	US-PGPUB; USPAT; USOCR; FPRS	SAME	ON	2007/11/20 10:35
S12 0	0	semicondutor adj wafer wir$3 and probe adj card near6 bumps	US-PGPUB; USPAT; USOCR; FPRS	SAME	ON	2007/11/20 10:35
S12 1	50	semiconductor adj wafer wir$3 and probe adj card near6 bumps	US-PGPUB; USPAT; USOCR; FPRS	SAME	ON	2007/11/20 10:35
S12 2	751	semiconductor adj wafer wir$3 and (probe adj card or burn$in)	US-PGPUB; USPAT; USOCR; FPRS	SAME	ON	2007/11/20 10:36
S12 3	504	semiconductor adj wafer wir$3 and (probe adj card or burn$in) and @ad<"20030922"	US-PGPUB; USPAT; USOCR; FPRS	SAME	ON	2007/11/20 10:36

EAST Search History

S124	8	("20020000655" | "20020089058" | "20020167075" | "6277669" | "6392287" | "6396145" | "6423571" | "6555908").PN. OR ("7084498").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/11/20 10:48
S125	8	("20020000655" | "20020089058" | "20020167075" | "6277669" | "6392287" | "6396145" | "6423571" | "6555908").PN. OR ("7084498").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/11/20 10:48
S126	8	("20020000655" | "20020089058" | "20020167075" | "6277669" | "6392287" | "6396145" | "6423571" | "6555908").PN. OR ("7084498").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/11/20 10:48
S127	7	("5293037" | "5508228" | "5956605" | "5994783").PN. OR ("6392287").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/11/20 10:51
S128	56	burn$in test (conduct$2 or perform$2)wir$3	US-PGPUB; USPAT; USOCR; FPRS	WITH	ON	2007/11/20 10:54
S129	287	probe test (conduct$2 or perform$2)wir$3	US-PGPUB; USPAT; USOCR; FPRS	WITH	ON	2007/11/20 10:54
S130	0	probe test (conduct$2 or perform$2)wir$3 and@ad<"20030922"	US-PGPUB; USPAT; USOCR; FPRS	WITH	ON	2007/11/20 10:55
S131	196	probe test (conduct$2 or perform$2)wir$3 and @ad<"20030922"	US-PGPUB; USPAT; USOCR; FPRS	WITH	ON	2007/11/20 10:55
S132	15	probe bump (contact$3) terminal wir$3 and @ad<"20030922"	US-PGPUB; USPAT; USOCR; FPRS	WITH	ON	2007/11/20 10:56
S133	9	("4894605" | "5166602" | "5397996" | "5506510").PN. OR ("6249114").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/11/20 10:57
S134	47	("3249926" | "4301403" | "4479088" | "4509008" | "4586242" | "4638246" | "4707654" | "4779041").PN. OR ("4894605"). URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/11/20 10:58
S136	10	(first and second)near(terminals or wir$3) same contact$3 one adj probe (contact or bump or ball)	US-PGPUB; USPAT; USOCR; FPRS	SAME	ON	2007/11/20 14:06
S137	0	(first and second)near(wir$3) contact$3 one adj probe near(contact or bump or ball)	US-PGPUB; USPAT; USOCR; FPRS	SAME	ON	2007/11/20 14:07
S138	0	(first and second or two)near(wir$3) contact$3 one adj probe near(contact or bump or ball)	US-PGPUB; USPAT; USOCR; FPRS	SAME	ON	2007/11/20 14:07
S139	0	(first and second or two)near(wir$3) one adj probe near(contact or bump or ball)	US-PGPUB; USPAT; USOCR; FPRS	SAME	ON	2007/11/20 14:08
S140	0	(first and second or two)near(wir$3) one adj prob$3 near(contact or bump or ball)	US-PGPUB; USPAT; USOCR; FPRS	SAME	ON	2007/11/20 14:08

S141	98	(first and second or two)near(wir$3) prob$3 near(contact or bump or ball)	US-PGPUB; USPAT; USOCR; FPRS	SAME	ON	2007/11/20 14:11
S142	71	(first and second or two or multiple or plural$3)near(wires or leads otr terminals) prob$3 near(contact or bump or ball)	US-PGPUB; USPAT; USOCR; FPRS	SAME	ON	2007/11/20 14:14
S143	62	(first and second or two or multiple or plural$3)near(wires or leads otr terminals) probe near(contact or bump or ball)	US-PGPUB; USPAT; USOCR; FPRS	SAME	ON	2007/11/20 14:14